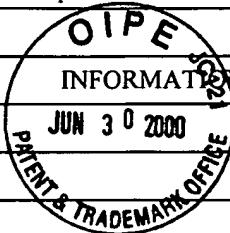


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A. Jenkins

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-7677 US		Unknown	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicants			
(Use several sheets if necessary)					Blaine R. Spady and John D. Heaton			
					Filing Date		Group	
					Unknown		Unknown	
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
PGW	AA	5,682,242	10/28/97	Eylon	356	401		
	AB	5,764,365	6/9/98	Finarov	356	381		
	AC	5,517,312	5/14/96	Finarov	356	386		
	AD	5,604,344	2/18/97	Finarov	250	201.3		
	AE	5,867,590	2/2/99	Eylon	382	151		
	AF	5,917,601	6/29/99	Shimazaki et al.	356	375		
	AG	5,957,749	9/28/99	Finarov	451	6		
	AH	5,910,846	6/8/99	Sandhu	356	381		
	AI							
	AJ							
	AK							
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
PGW	AL	EP 0 893 203 A2	1/27/99	Europe				
	AM	WO 99/15710	4/1/99	WIPO				
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
PGW	AQ	Peter Rosenthal, "Integrated FTIR reflectometer controls semiconductor fabrication process", (Laser Focus World, April 1998).						
	AR	Nova Measuring Instruments Ltd. NovaScan 420 (Ophir Optronics Ltd.).						
	AS							
Examiner		Date Considered						
PGW		3/14/00						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-7677 US		09/458,123	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicants			
(Use several sheets if necessary)					Heaton, John D.; Spady, Blaine R.			
					Filing Date		Group	
					12/08/99		2877	
U.S. Patent Documents								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
fgn	AA 5,730,642	03/24/98	Sandhu et al.	451	6			
✓	AB 6,038,029	03/14/00	Finarov	356	399			
	AC							
	AD							
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	AJ							
	AK							
Foreign Patent Documents								
							Translation	
	Document	Date	Country	Class	Subclass	Yes	No	
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ							
	AR							
	AS							
Examiner <i>fgm</i>		Date Considered <i>3/14/3</i>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.		Serial No.	
 INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				M-7677 US		09/458,123	
				Applicant(s)			
				Heaton, John D.; Spady, Blaine R.			
				Filing Date		Group	
				12/08/1999			

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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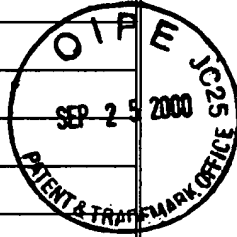
Foreign Patent Documents							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
<i>pcn</i>	AL	WO 00/28577	18 May 2000	PCT				
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
	AQ	
	AR	
	AS	

Examiner <i>Pruva</i>	Date Considered <i>3/13/7</i>
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U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-7677 US		09/458,123	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicants			
(Use several sheets if necessary)					Heaton, John D.; Spady, Blaine R.			
					Filing Date		Group	
					12/08/1999		2877	
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
PCW	AA	6,111,634	08/29/00	Pecen et al.	356	72		
	AB							
	AC							
	AD							
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	AG							
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	AN							
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ							
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	AS							
Examiner		Date Considered						
PCW		3/13/3						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								



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